Power MOSFET

30 V, 58.5 A, Single N-Channel, SO-8 FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Dual Sided Cooling Capability
- These are Pb-Free Device

Applications

- CPU Power Delivery
- DC-DC Converters
- High Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage		V_{GS}	±20	V	
Continuous Drain Current R _{θJA}		$T_A = 25^{\circ}C$ $T_A = 85^{\circ}C$	Ι _D	13.8 10	Α
(Note 1) Power Dissipation R _{0,JA} (Note 1)		T _A = 25°C	P _D	2.14	W
Continuous Drain Current R _{θJA} ≤ 10 sec		T _A = 25°C T _A = 85°C	I _D	22.4 16.1	Α
Power Dissipation $R_{\theta JA}$, $t \le 10$ sec	Steady State	T _A = 25°C	P _D	5.61	W
Continuous Drain Current R _{0.IA}		T _A = 25°C	I _D	8.8	Α
(Note 2)		T _A = 85°C		6.4	
Power Dissipation R _{θJA} (Note 2)		T _A = 25°C	P _D	0.87	W
Continuous Drain Current R _{e.IC}		T _C = 25°C	I _D	58.5	Α
(Note 1)		T _C = 85°C		42.3	
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	38.5	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	117	Α
Current limited by pa	ckage	T _A = 25°C	I _{Dmaxpkg}	100	Α
Operating Junction and Storage Temperature		T _J , T _{STG}	-40 to +150	°C	
Source Current (Body Diode)		I _S	38.5	Α	
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain–to–Source Avalanche Energy (V_{DD} = 50 V, V_{GS} = 10 V, I_{L} = 24 A_{pk} , L = 0.3 mH, R_{G} = 25 Ω)		EAS	86	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

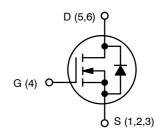
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



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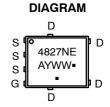
http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	6.95 m Ω @ 10 V	58.5 A
	10.8 mΩ @ 4.5 V	46.9 A



N-CHANNEL MOSFET





MARKING

Α = Assembly Location

WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4827NET1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4827NET3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.25	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	58.3	1
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	144.1	°C/W
Junction-to-Ambient - t ≤ 10 sec	$R_{ heta JA}$	22.3	
Junction-to-Top	$R_{ heta JT}$	9.8	

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•	•	•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_D = 250 μA		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	I_{DSS} $V_{GS} = 0 V$,				1	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$				±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		1.45	1.8	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J						mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to	I _D = 30 A		5.3	6.95	
		11.5 V	I _D = 15 A		5.2		
		V _{GS} = 4.5 V	I _D = 30 A		8.6	10.8	mΩ
			I _D = 15 A		8.4		
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 30 A			54		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				1400		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			282		pF
Reverse Transfer Capacitance	C _{RSS}				136		
Total Gate Charge	Q _{G(TOT)}				10.7	16	
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			1.4		nC
Gate-to-Source Charge	Q_{GS}				4.1		
Gate-to-Drain Charge	Q_{GD}				3.8		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V, I _D = 30 A			25		nC
SWITCHING CHARACTERISTICS (Note 4)	-			-			-
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			13.3		
Rise Time	t _r				38		1
Turn-Off Delay Time	t _{d(OFF)}				16.6		ns
Fall Time	t _f				3.8		1

- 3. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 4. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)						
Turn-On Delay Time	t _{d(ON)}			8.2		- ns	
Rise Time	t _r	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			20		
Turn-Off Delay Time	t _{d(OFF)}				23		
Fall Time	t _f				3.1		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 30 A	T _J = 25°C		0.85	1.0	.,
			T _J = 125°C		0.74		V
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dI_S/dt = 100 A/ μ s, I_S = 30 A			11		ns
Charge Time	t _a				7.5		
Discharge Time	t _b				3.5		
Reverse Recovery Charge	Q _{RR}				2.0		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	T _A = 25°C			1.3		nΗ
Drain Inductance	L _D				0.005		1
Gate Inductance	L _G				1.84		
Gate Resistance	R_{G}			0.5	1.1	2.0	Ω

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

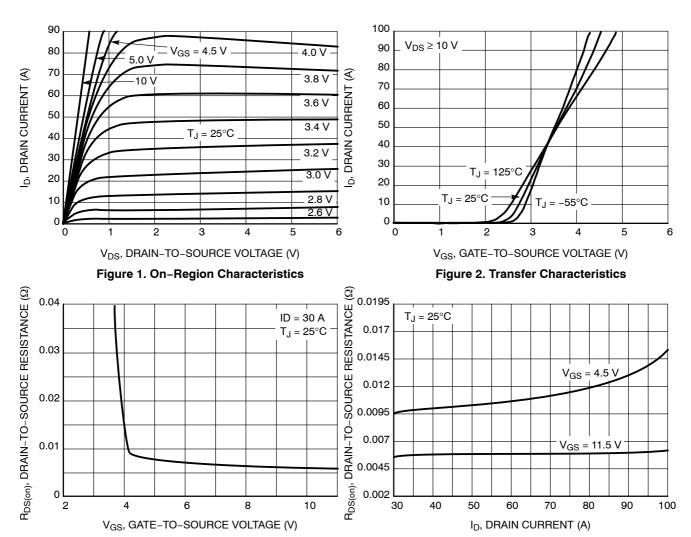


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage

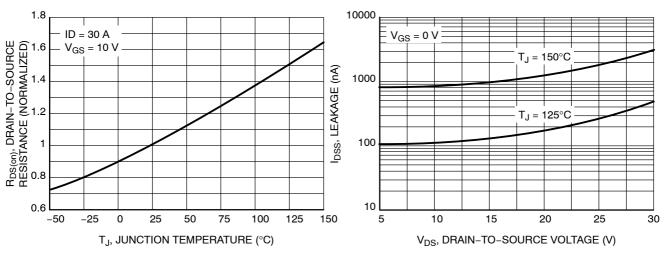


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES

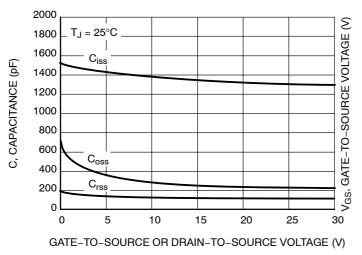
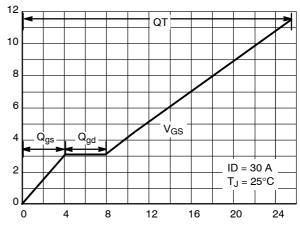


Figure 7. Capacitance Variation



Q_q, TOTAL GATE CHARGE (nC)

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

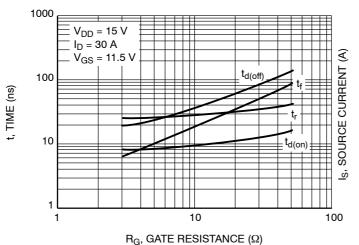


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

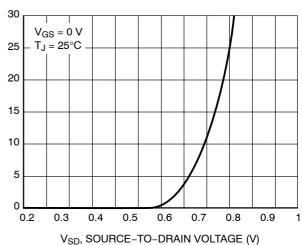


Figure 10. Diode Forward Voltage vs. Current

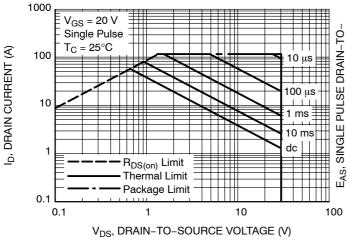
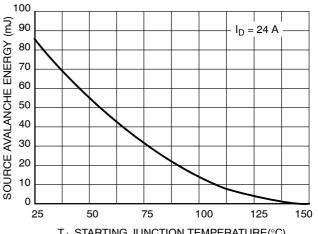


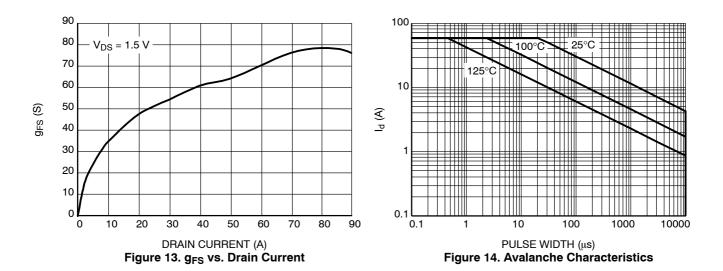
Figure 11. Maximum Rated Forward Biased Safe Operating Area



T_{.J}, STARTING JUNCTION TEMPERATURE(°C)

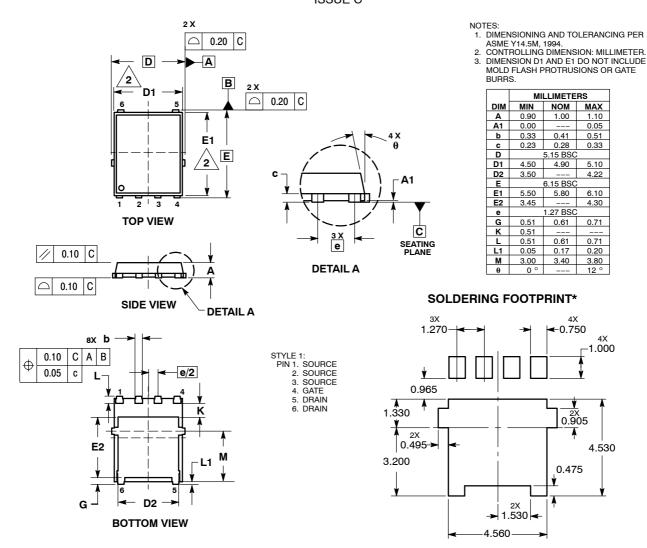
Figure 12. Maximum Avalanche Energy vs. **Starting Junction Temperature**

TYPICAL PERFORMANCE CURVES



PACKAGE DIMENSIONS

DFN6 5x6, 1.27P (SO8 FL)CASE 488AA-01 ISSUE C



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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